Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/611,611	DEHNE ET AL.	
Examiner	Art Unit	
Mark A. Deuble	3651	

SEARCHED				
Class	Subclass	Date	Examiner	
ABOVE	UPDATED	8/30/2006	MD	
-			_	
	_			
_				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH (INCLUDING SEAI	NOTES RCH STRATEG	Y)
	DATE	EXMR
	-	
		_
		1
		1